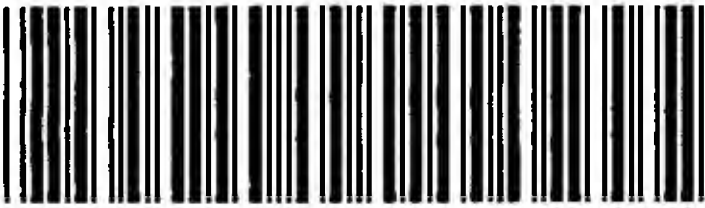


<div>Search Notes</div> <div></div>	Application/Control No. ,	Applicant(s)/Patent under Reexamination	
	10/594,928	LEE ET AL.	
	Examiner	Art Unit	
	Tan Ho	2821	

SEARCHED			
Class	Subclass	Date	Examiner
343	702	11/20/07	T.H.
↓	895	↓	↓
↓	793	↓	↓
455	90.3	✓	✓

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
<div></div>		